

Nell High Power Products

N-Channel Power MOSFET (57A, 100Volts)

DESCRIPTION

The Nell **IRF3710** are N-channel enhancement mode silicon gate power field effect transistors.

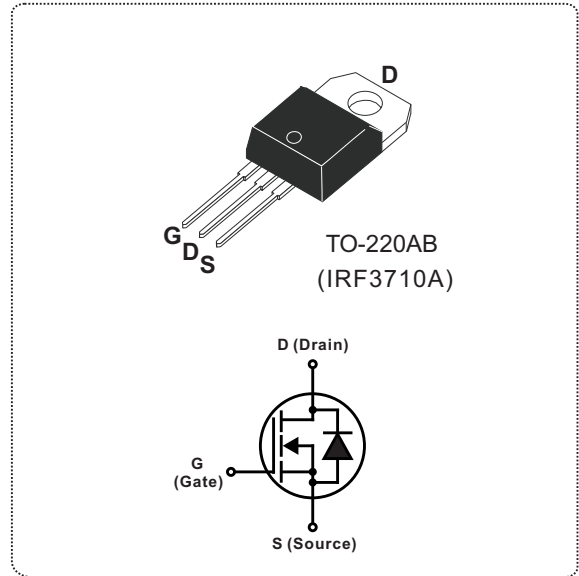
They are designed, tested and guaranteed to withstand level of energy in breakdown avalanche mode of operation.

They are designed as an extremely efficient and reliable device for use in a wide variety of applications such as switching regulators, converters, motor drivers and drivers for high power bipolar switching transistors requiring high speed and low gate drive power.

These transistors can be operated directly from integrated circuits.

FEATURES

- $R_{DS(ON)} = 0.023\Omega @ V_{GS} = 10V$
- Ultra low gate charge(130nC max.)
- Low reverse transfer capacitance ($C_{RSS} = 72pF$ typical)
- Fast switching capability
- 100% avalanche energy specified
- Improved dv/dt capability
- 175°C operation temperature



PRODUCT SUMMARY	
I_D (A)	57
V_{DSS} (V)	100
$R_{DS(ON)}$ (Ω)	0.023 @ $V_{GS} = 10V$
Q_G (nC) max.	130

ABSOLUTE MAXIMUM RATINGS ($T_C = 25^\circ C$ unless otherwise specified)				
SYMBOL	PARAMETER	TEST CONDITIONS	VALUE	UNIT
V_{DSS}	Drain to Source voltage(Note 1)	$T_J = 25^\circ C$ to $150^\circ C$	100	
V_{DGR}	Drain to Gate voltage	$R_{GS} = 20K\Omega$	100	V
V_{GS}	Gate to Source voltage		± 20	
I_D	Continuous Drain Current	$V_{GS} = 10V, T_C = 25^\circ C$	57	A
		$V_{GS} = 10V, T_C = 100^\circ C$	40	
I_{DM}	Pulsed Drain current (Note 1)		230	
I_{AR}	Repetitive avalanche current (Note 1)		28	
E_{AR}	Repetitive avalanche energy(Note 1)	$I_{AR} = 28A, R_{GS} = 50\Omega, V_{GS} = 10V$	20	mJ
E_{AS}	Single pulse avalanche energy (Note 2)	$I_{AS} = 28A, L = 0.7mH$	280	mJ
dv/dt	Peak diode recovery dv/dt(Note 3)		5.8	V/ns
P_D	Total power dissipation	$T_C = 25^\circ C$	200	W
	Derating factor above $25^\circ C$		1.3	W/ $^\circ C$
T_J	Operation junction temperature		-55 to 175	
T_{STG}	Storage temperature		-55 to 175	$^\circ C$
T_L	Maximum soldering temperature, for 10 seconds	1.6mm from case	300	
	Mounting torque, #6-32 or M3 screw		10 (1.1)	lbf-in (N·m)

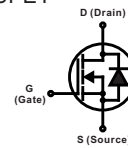
Note: 1. Repetitive rating: pulse width limited by junction temperature.

2. $V_{DD} = 50V, L = 0.7mH, I_{AS} = 28A, R_G = 25\Omega, T_J = 175^\circ C$

3. $I_{SD} \leq 28A, di/dt \leq 380A/\mu s, V_{DD} \leq V_{(BR)DSS}, T_J \leq 175^\circ C$.

THERMAL RESISTANCE					
SYMBOL	PARAMETER	Min.	Typ.	Max.	UNIT
$R_{th(j-c)}$	Thermal resistance, junction to case			0.75	
$R_{th(c-s)}$	Thermal resistance, case to heatsink		0.5		°C/W
$R_{th(j-a)}$	Thermal resistance, junction to ambient			62	

ELECTRICAL CHARACTERISTICS ($T_C = 25^\circ\text{C}$ unless otherwise specified)						
SYMBOL	PARAMETER	TEST CONDITIONS	Min.	Typ.	Max.	UNIT
⊙ STATIC						
$V_{(BR)DSS}$	Drain to source breakdown voltage	$V_{GS} = 0V, I_D = 250\mu A$	100			V
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown voltage temperature coefficient	$I_D = 1mA$, referenced to 25°C		0.13		V/°C
I_{DSS}	Drain to source leakage current	$V_{DS} = 100V, V_{GS} = 0V$ $T_C = 25^\circ\text{C}$			25	μA
		$V_{DS} = 80V, V_{GS} = 0V$ $T_C = 150^\circ\text{C}$			250	
I_{GSS}	Gate to source forward leakage current	$V_{GS} = 20V, V_{DS} = 0V$			100	nA
	Gate to source reverse leakage current	$V_{GS} = -20V, V_{DS} = 0V$			-100	
$R_{DS(ON)}$	Static drain to source on-state resistance	$V_{GS} = 10V, I_D = 28A$ (Note 1)			0.023	Ω
$V_{GS(TH)}$	Gate threshold voltage	$V_{GS} = V_{DS}, I_D = 250\mu A$	2		4	V
g_{fs}	Forward transconductance	$V_{DS} = 25V, I_D = 28A$	32			S
⊙ DYNAMIC						
C_{ISS}	Input capacitance	$V_{DS} = 25V, V_{GS} = 0V, f = 1MHz$		3130		pF
C_{OSS}	Output capacitance			410		
C_{RSS}	Reverse transfer capacitance			72		
$t_{d(ON)}$	Turn-on delay time	$V_{DD} = 50V, I_D = 28A$ $V_{GS} = 10V, R_G = 2.5\Omega$ (Note 1)		12		ns
t_r	Rise time			58		
$t_{d(OFF)}$	Turn-off delay time			45		
t_f	Fall time			47		
L_D	Internal drain inductance	Between lead, 6mm from package and center of die		4.5		nH
L_S	Internal source inductance			7.5		
Q_G	Total gate charge	$V_{DS} = 80V, V_{GS} = 10V, I_D = 28A$			130	nC
Q_{GS}	Gate to source charge				26	
Q_{GD}	Gate to drain charge (Miller charge)				43	

SOURCE TO DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_C = 25^\circ\text{C}$ unless otherwise specified)						
SYMBOL	PARAMETER	TEST CONDITIONS	Min.	Typ.	Max.	UNIT
V_{SD}	Diode forward voltage	$I_{SD} = 28A, V_{GS} = 0V$			1.2	V
$I_S(I_{SD})$	Continuous source to drain current	Integral reverse P-N junction diode in the MOSFET 			57	A
I_{SM}	Pulsed source current				230	
t_{rr}	Reverse recovery time	$I_{SD} = 28A, V_{GS} = 0V,$ $dI_F/dt = 100A/\mu s$		140	220	ns
Q_{rr}	Reverse recovery charge			670	1010	nC
t_{ON}	Forward turn-on time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S + L_D$)				

Note: 1. Pulse test: Pulse width $\leq 400\mu s$, duty cycle $\leq 2\%$.

ORDERING INFORMATION SCHEME

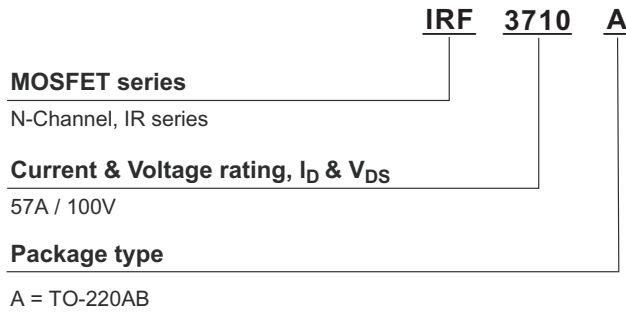


Fig.1 Typical output characteristics, $T_C=25^\circ\text{C}$

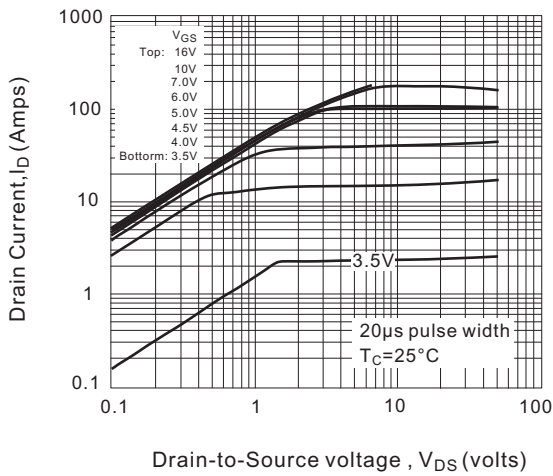


Fig.2 Typical output characteristics, $T_C=150^\circ\text{C}$

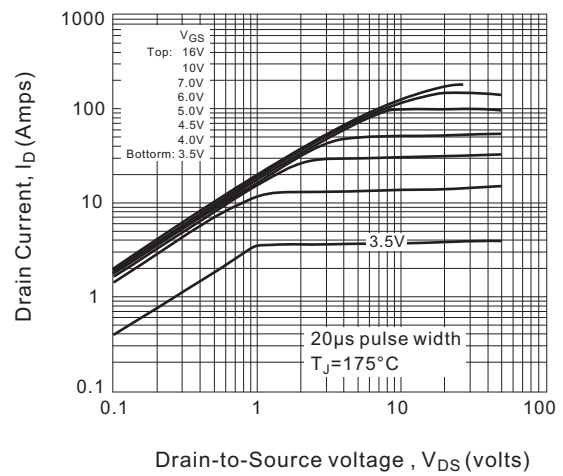


Fig.3 Typical transfer characteristics

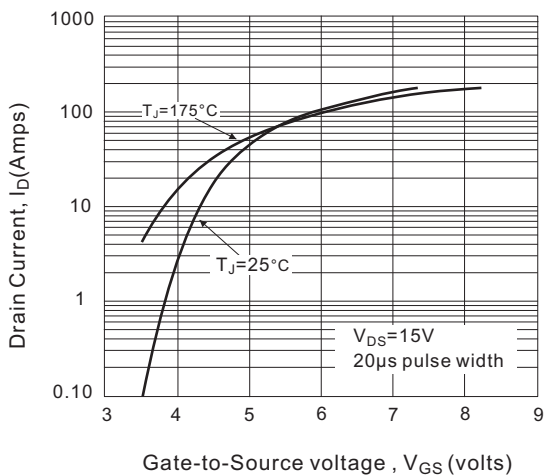


Fig.4 Normalized On-Resistance vs. Temperature

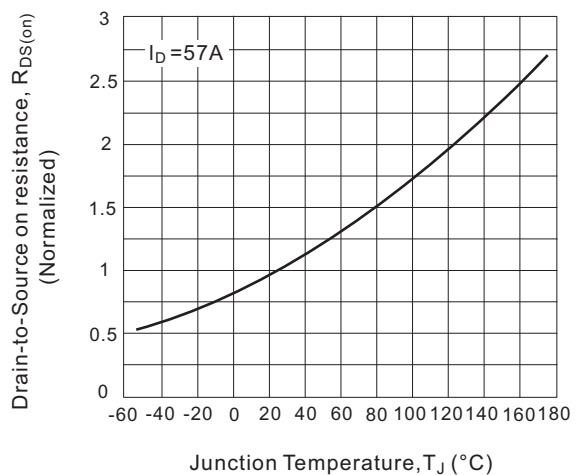


Fig.5 Typical capacitance vs. Drain-to-Source voltage

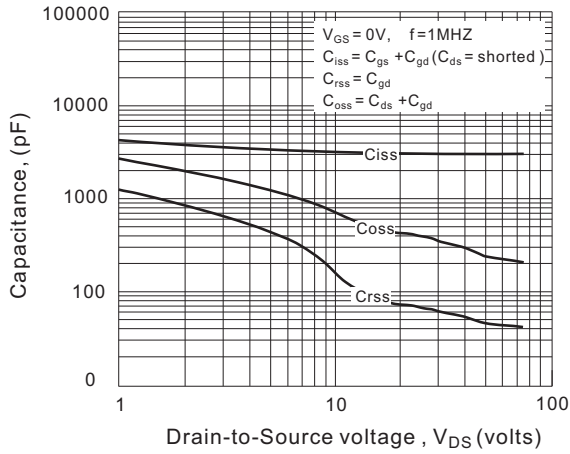


Fig.6 Typical source-drain diode forward voltage

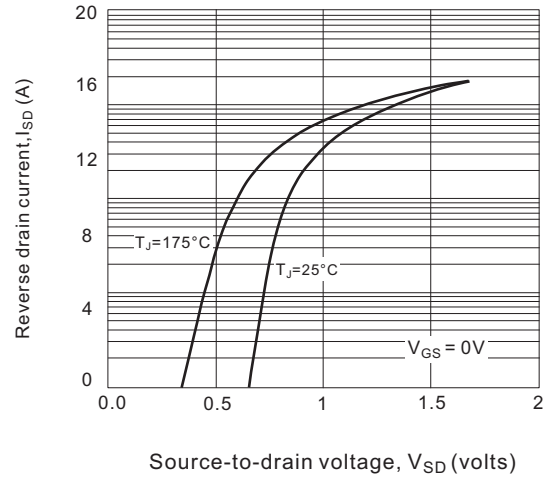


Fig.7 Typical gate charge vs. gate-to-source voltage

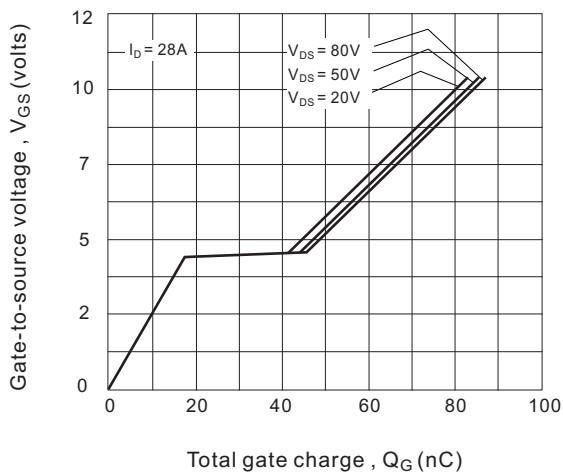


Fig.8 Maximum safe operating area

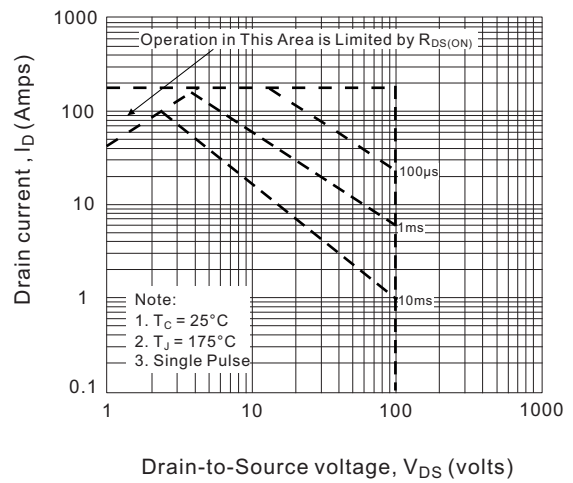


Fig.9 Maximum drain current vs. Case temperature

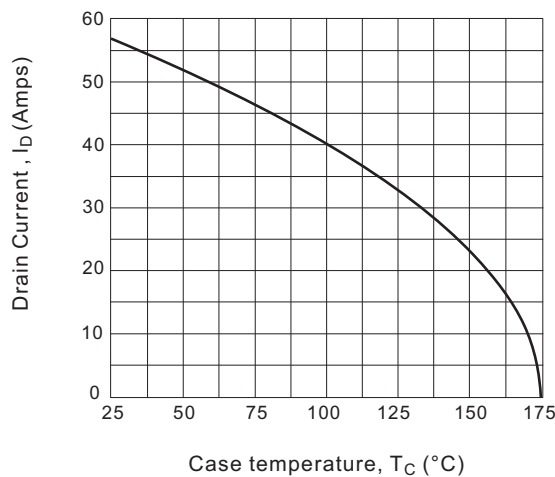


Fig.10 Maximum effective transient thermal impedance, Junction-to-Case

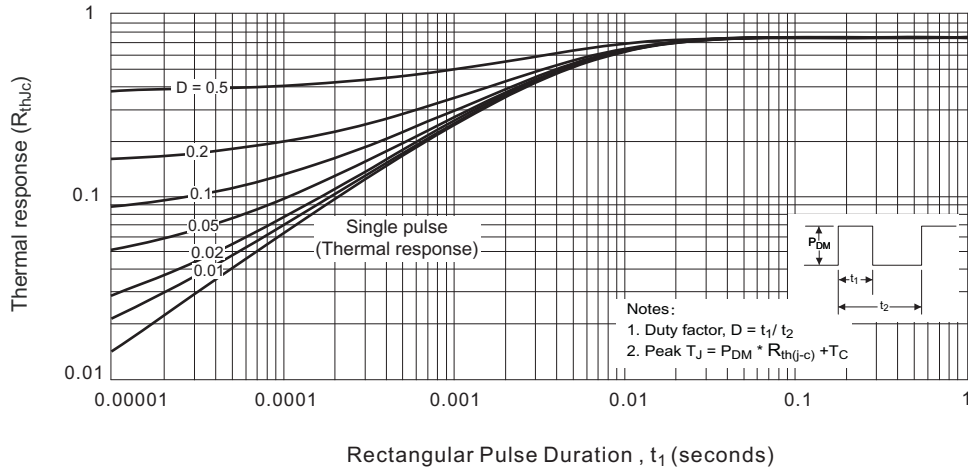


Fig.11a. Switching time test circuit

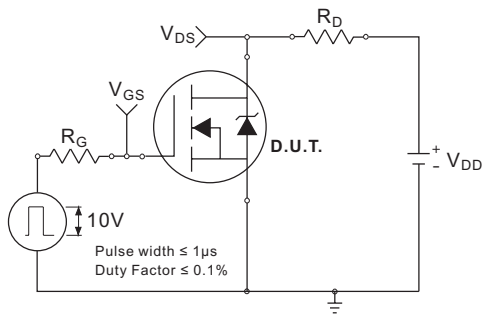


Fig.11b. Switching time waveforms

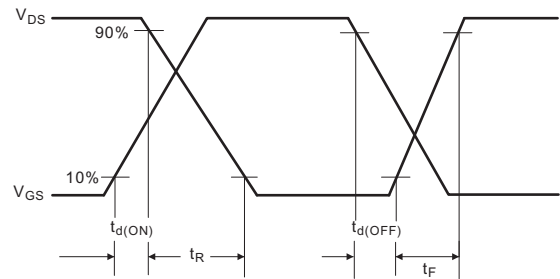
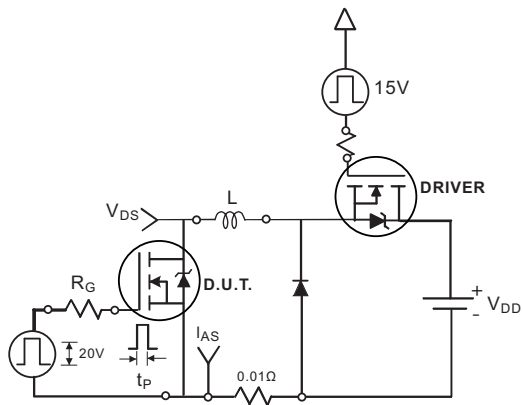


Fig.12a. Unclamped Inductive test circuit



Vary t_p to obtain required I_{AS}

Fig.12b. Unclamped Inductive waveforms

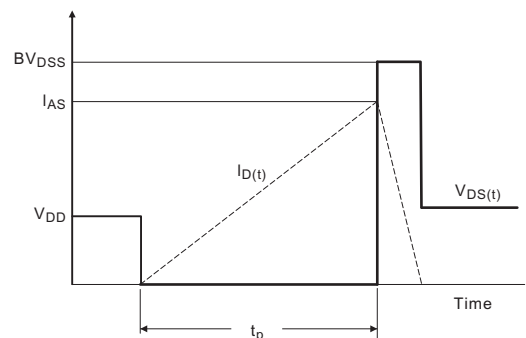


Fig.12c. Maximum avalanche energy vs. Drain current

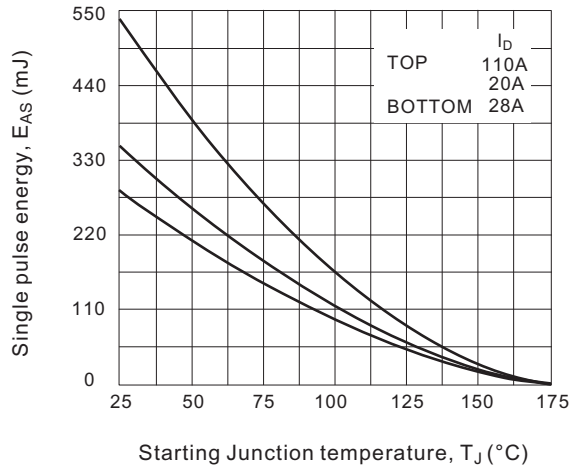


Fig.13a. Basic gate charge waveform

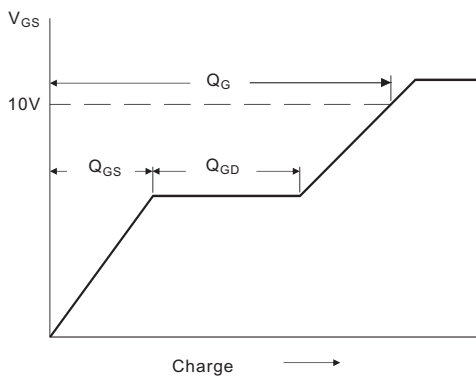


Fig.13b. Gate charge test circuit

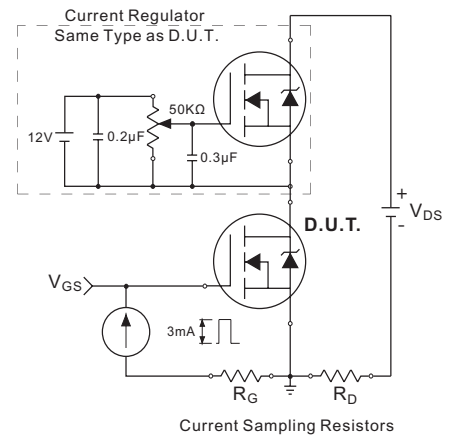
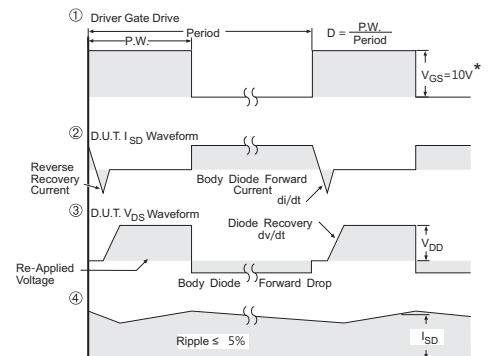
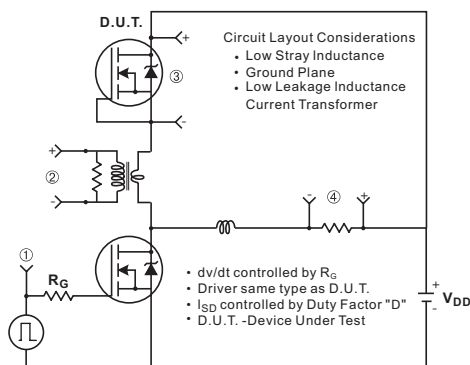
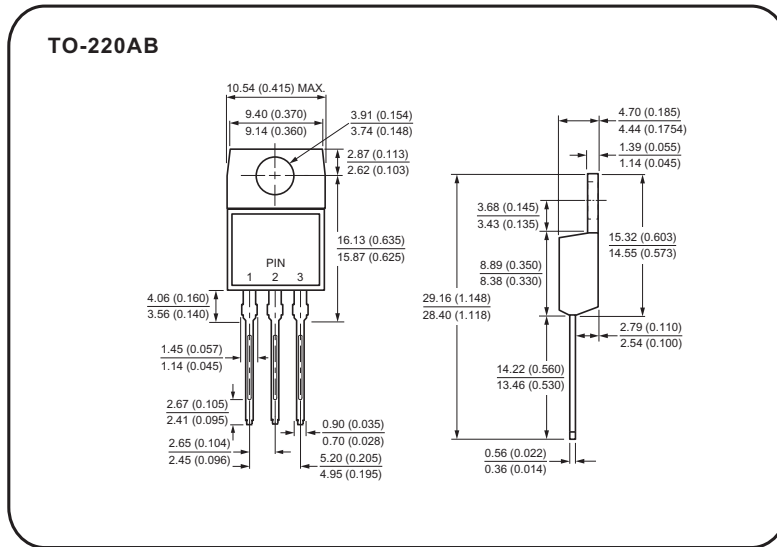


Fig.14 Peak diode recovery dv/dt test circuit for N-Channel MOSFET



* $V_{GS} = 5V$ for Logic Level Devices and $3V$ for drive devices

Case Style



All dimensions in millimeters(inches)

